



CERTIFICATE OF ACCREDITATION

ANSI-ASQ National Accreditation Board

500 Montgomery Street, Suite 625, Alexandria, VA 22314, 877-344-3044

This is to certify that

**IEC Electronics Analysis & Testing Laboratory
(IATL)**

**1430 Mission Avenue
Albuquerque, NM 87107**

has been assessed by ANAB
and meets the requirements of international standard

ISO/IEC 17025:2005

while demonstrating technical competence in the field(s) of

TESTING

Refer to the accompanying Scope(s) of Accreditation for information regarding the types of tests to which this accreditation applies.

AT-1572

Certificate Number

ANAB Approval

Certificate Valid: 01/11/2016-10/12/2017

Version No. 002 Issued: 01/11/2016



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated January 2009).



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005

IEC Electronics Analysis & Testing Laboratory (IATL)

1430 Mission Ave., Albuquerque, NM 87107

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TESTING

Valid to: October 12, 2017

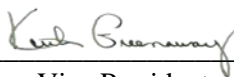
Certificate Number: AT - 1572

FIELD OF TEST	ITEMS, MATERIALS OR PRODUCTS TESTED	SPECIFIC TESTS OR PROPERTIES MEASURED	SPECIFICATION, STANDARD METHOD OR TECHNIQUE USED	*KEY EQUIPMENT OR TECHNOLOGY
Non-Destructive Testing (NDT)	Electrical, Electronic and Electromechanical (EEE) Components	Elemental content by XRF, EDS (Lead, tin, etc.)	JESD213	Fischerscope XDAL
Non-Destructive Testing (NDT)	Electrical, Electronic and Electromechanical (EEE) Components	Elemental thickness XRF (ENIG)	IPC-4552	Fischerscope XDAL
Non-Destructive Testing (NDT)	Electrical, Electronic and Electromechanical (EEE) Components	Radiographic Examination / Inspection	MIL-STD-883, Method 2012 MIL-STD-750, Method 2076 MIL-STD-202, Method 209	Nordson Dage XD7600NT Ruby
Non-Destructive Testing (NDT)	Electrical, Electronic and Electromechanical (EEE) Components	Acoustic Microscopy (CSAM) Examination / Inspection	IPC/JEDEC J-STD-035	Sonix Echo
Mechanical	Electrical, Electronic and Electromechanical (EEE) Components	SEM Examination / Inspection	MIL-STD-750, Method 2077 MIL-STD-883, Method 2018	Hitachi S-4800
Mechanical	Electrical, Electronic and Electromechanical (EEE) Components	Internal Examination / Inspection	MIL-STD-883, Method 2010 and 2013 MIL-STD-750 Method 2072	Olympus BX50 Keyence VHX- 2000E
Mechanical	Electrical, Electronic and Electromechanical (EEE) Components	Particle Impact Noise Detection (PIND)	MIL-STD-883, Method 2020 MIL-STD-750, Method 2052	Spectral Dynamics PTI Model: 4511 I
Mechanical	Electrical, Electronic and Electromechanical (EEE) Components	Die Shear Grams of Force	MIL-STD-883, Method 2019 MIL-STD-750, Method 2017	Dage 4000

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Environmental	Electrical, Electronic and Electromechanical (EEE) Components	Fine Leak Testing Leak Rate	MIL-STD-883, Method 1014; MIL-STD-750, Method 1071; MIL-STD-202, Method 112	Alcatel ASM 142
Environmental	Electrical, Electronic and Electromechanical (EEE) Components	Gross Leak Testing Examination / Inspection	MIL-STD-883, Method 1014; MIL-STD-750, Method 1071; MIL-STD-202, Method 112	Web Technologies 6000 Bubble Tester
Environmental	Electrical, Electronic and Electromechanical (EEE) Components	Exposure / Temperature Cycling	MIL-STD-883, Method 1010; MIL-STD-750, Method 1051;	Tenney JR T-Shock Chamber
Failure Analysis	Electrical, Electronic and Electromechanical (EEE) Components	Curve Trace	MIL-STD-883, Method 5003	JD Instruments ATE Tektronix 370
Failure Analysis	Polymers, Non-volatile Residue, Material Electrical, Electronic and Electromechanical (EEE) Components	Material Characterization	ASTM E 334	Nicolet 6700 Analytical FTIR Spectrometer and Continuum IR Microscope
Thermal Analysis Techniques	Polymers, Non-volatile Residue, Material Electrical, Electronic and Electromechanical (EEE) Components	Thermogravimetric Analysis (TGA)	ASTM E1131	TA Instruments Q50 Thermogravimetric Analyzer TGA

Notes:

1. * = As Applicable
2. This scope is formatted as part of a single document including the Certificate of Accreditation No. AT-1572



Vice President